

Excess of Power During Electrochemical Loading: Materials, Electrochemical Conditions and Techniques

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Remarks

Signals well above the measurement uncertainties are confirming the anomalous production of excess of power during electrochemical loading of Palladium with Deuterium.

Excess of power has the following features:

- 1) Threshold effect (loading D/Pd > 0.9)
- 2) Unobserved with hydrogen
- 3) Unexplainable as chemical effect
- 4) Occurs only if materials are showing specific characteristics



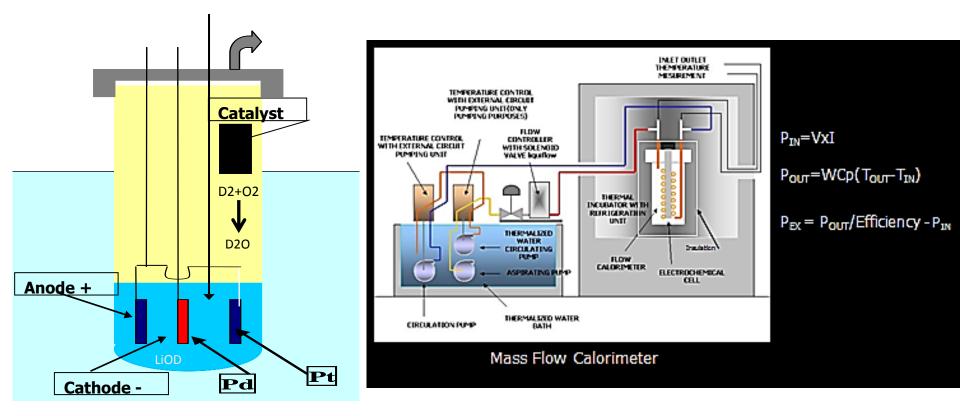
Research Approach



- 1) Material science to increase both reproducibility and signals by loading enhancement.
- 2) Calorimetric experiments designed to have an appropriate signal/noise ratio.
- 3) Definition of the effect through the material characteristics.



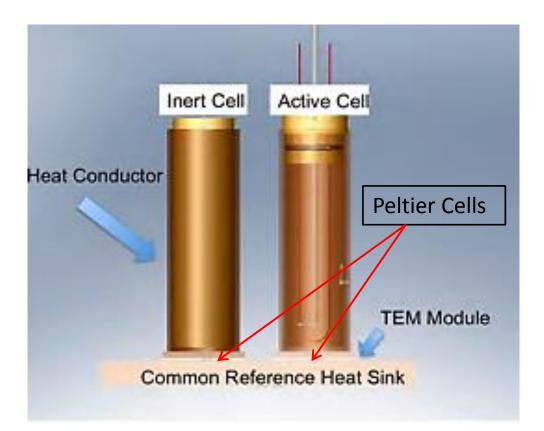
Calorimetry (Mass Flow): Closed Cells



Closed Electrochemical Cell



NRL Differential Calorimeter



Pout = $a + b^* \Delta V$ a= offset b=gain ΔV =ddp peltier



Observed Behaviors

Some differences were observed concerning Pd cathodes loaded above the threshold D/Pd = 0.9:

- 1) High power gain during the excess.
- 2) Low power gain during excess.
- 3) No excess.

The different behavior was related to some features of the samples ascribed to contaminants.



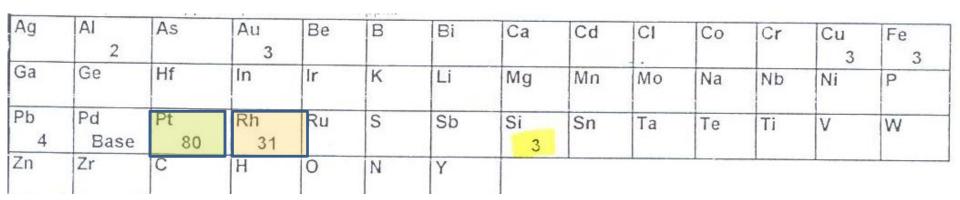
Differences in Two Lots from the Same Producer

Spectrum of Contaminants in the Rough Materials (from the producer).

Ag	AI	As	Au	Be	В	Bi	Ca	Cd	CI	Co	Cr	Cu	Fe
3	5		6	1	5	10	2	2		2	5	3	15
Ga	Ge	Ht	In	lir 12	K	Li	Mg 2	Mn 2	Mo 3	Na	Nb	Ni 5	P
Pb 5	Pd Base	Pt 190	Rh 12	Ru 3	S	Sb 5	Si 30	Sn 10	Ta	Te	Ti	V	W
Zn 5	Zr 20	С	Н	0	N	Y							

Both lots 99.95% purity

I lot: Reproducibility > 60%, Excess Power > 100%



II lot: Reproducibility < 20%, Excess Power < 20%



Effect of Contaminants

Contaminants may act on:

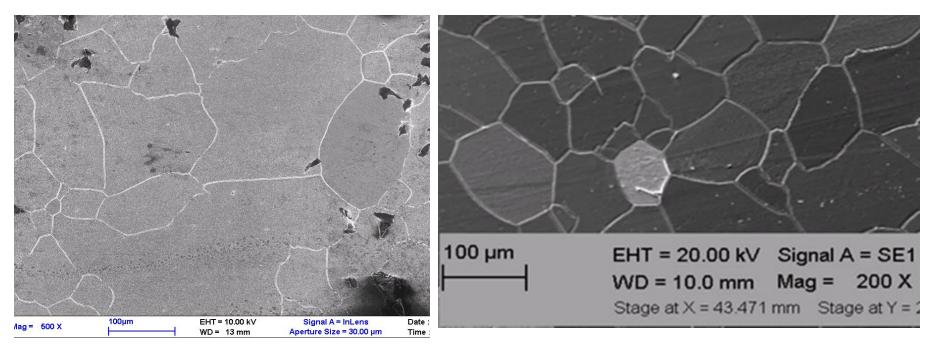
- Grain size
- Crystal orientation
- Grain boundary
- Surface treatment → Surface Morphology

Controls Kinetics and DL Capacitance

Controls Stress and Mass Transfer

Controls Stress and Mass Transfer

Acts on Kinetics and DL Capacitance



Lot 1 From the same producer; same tretment Lot 2



Identified Conditions to Observe the Effect in PdD System

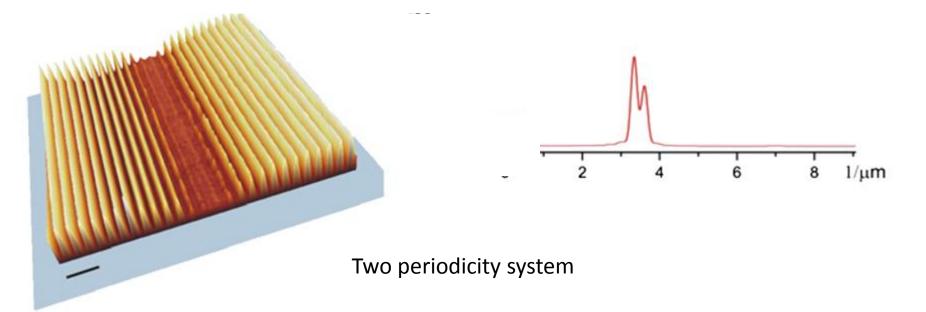
- 1) Appropriate metallurgy to achieve the loading threshold
- 2) Enhanced mass transfer
- 3) <100> mostly oriented material
- 4) Appropriate surface morphology



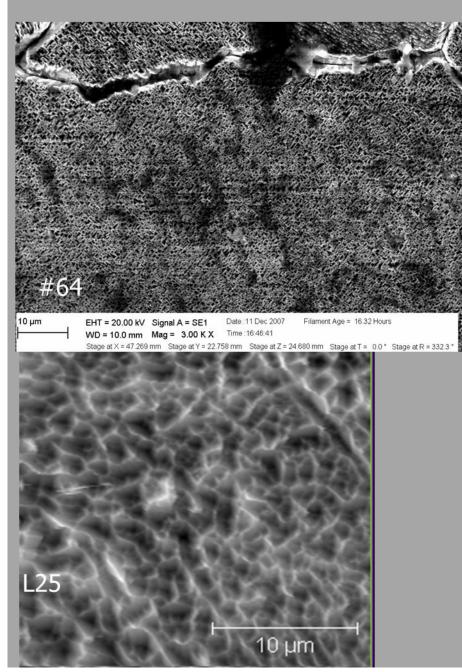
Surface

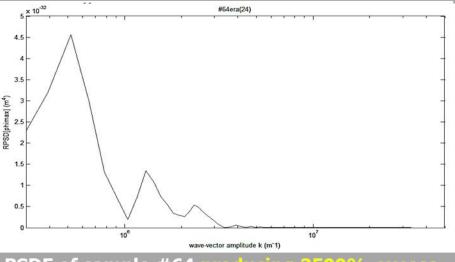
- Crystal orientation and specific contaminants modify the effect of the chemical etching leading a different surface status.
- -The surface morphology is acting on the interface electrochemical structure.

Power Spectral Density Function (PSDF) has been selected as surface merit figure.

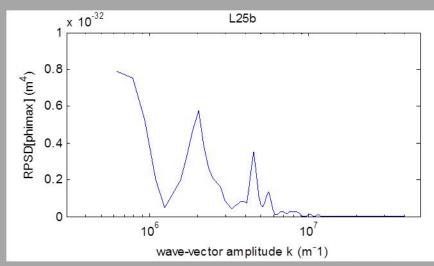


Typical Surface Morphology (after Etching) giving Excess of Heat



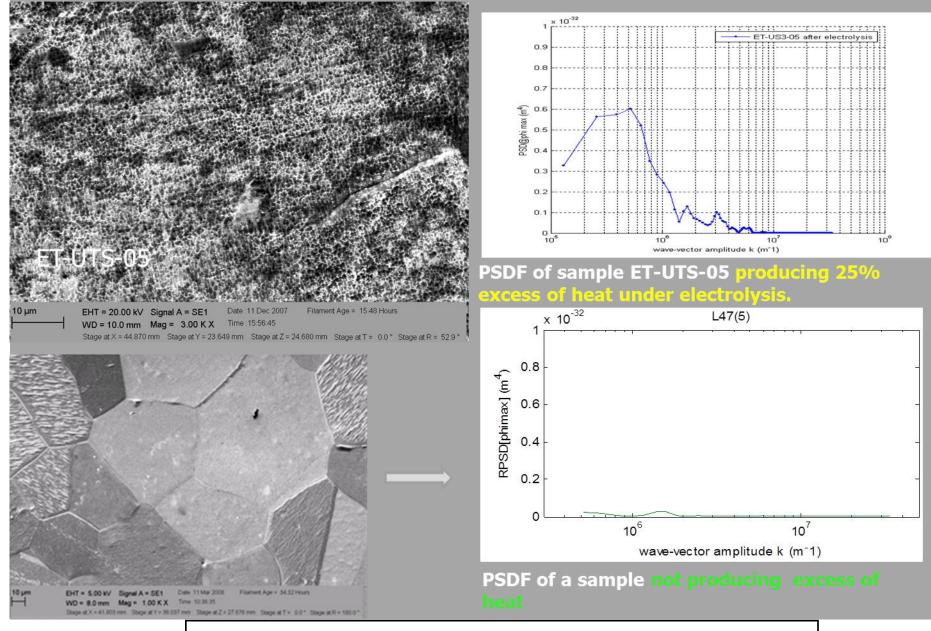


PSDF of sample #64 producing 3500% excess of heat.



PSDF of sample L25 producing up to 250% excess of heat.

The larger the PSDF amplitude the larger the excess of power



Surface morphology results to be a fourth condition



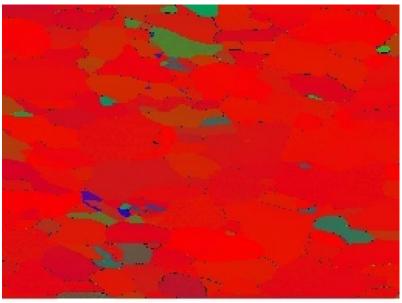
Now we play with contaminants

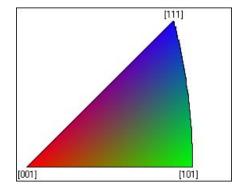


Producing an Active Material

The experimental evidences allowed to produce a material with characteristics close to the ones above described.

<u>A lot of Pd having a spectrum of contaminants approaching the lot 1</u> was undergone to the treatment leading to: dominant <100> orientation and an appropriate metallurgy.



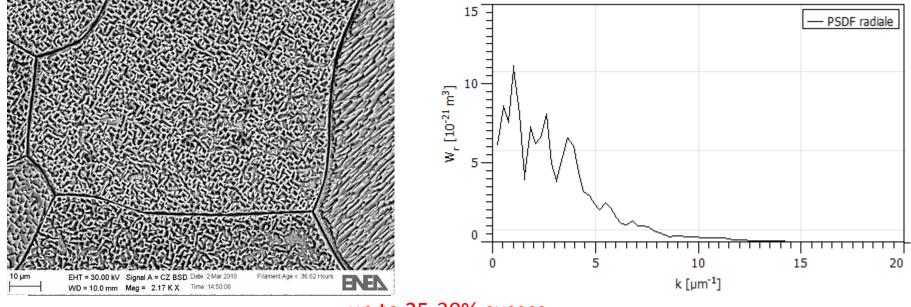


Sample Normal

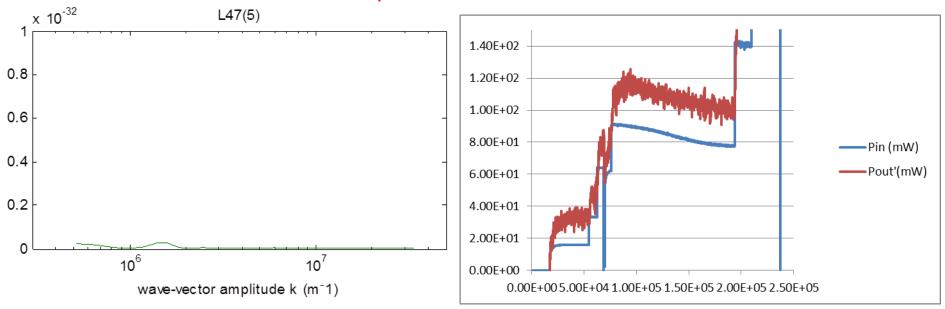
L66 ESBD Results

Palladium was doped by Platinum: effect on the surface

L66 (120-160) Platinum added







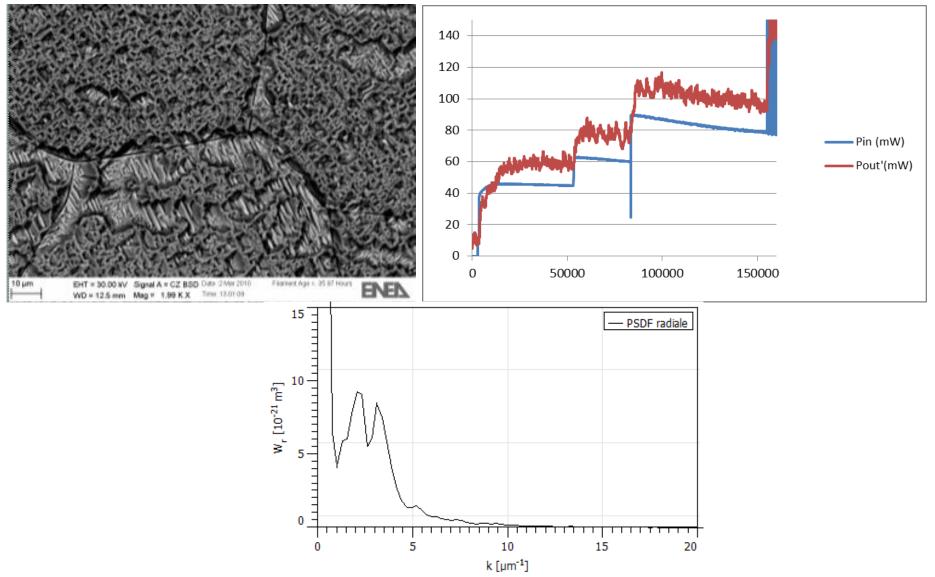
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L66 (160-200) Platinum added

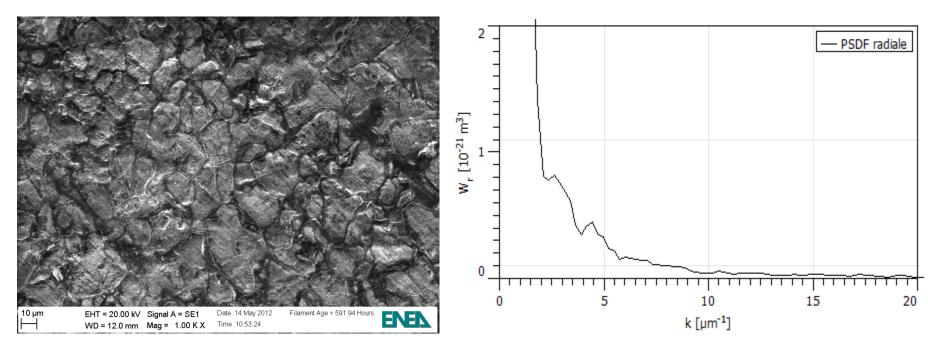
Again

up to 25-30% excess





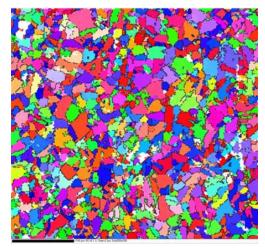
Palladium Rhodium Alloy produced at ENEA by using NRL protocol



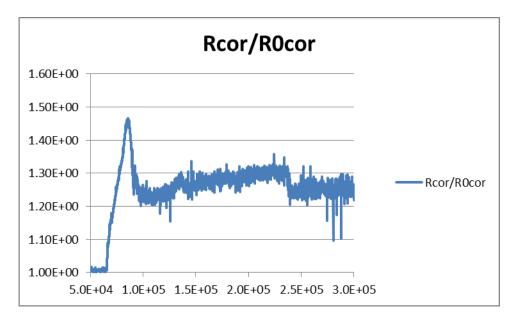
L119 (20-60) Before

L119 (20-60) PSD from AFM

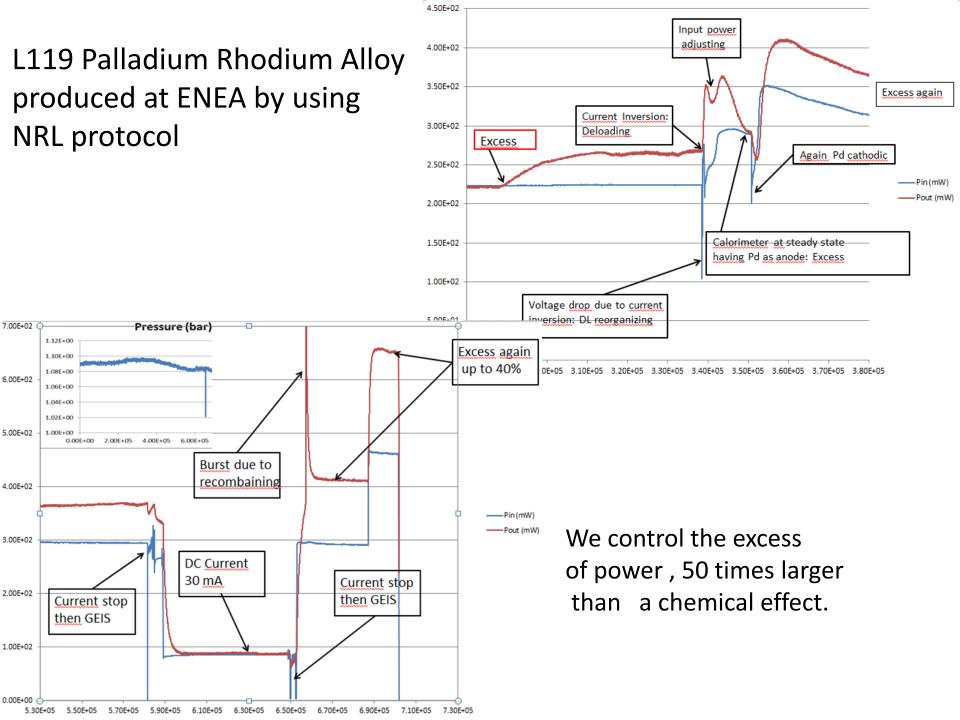




EBSD reveals a scattered orientation of crystals and small size grains

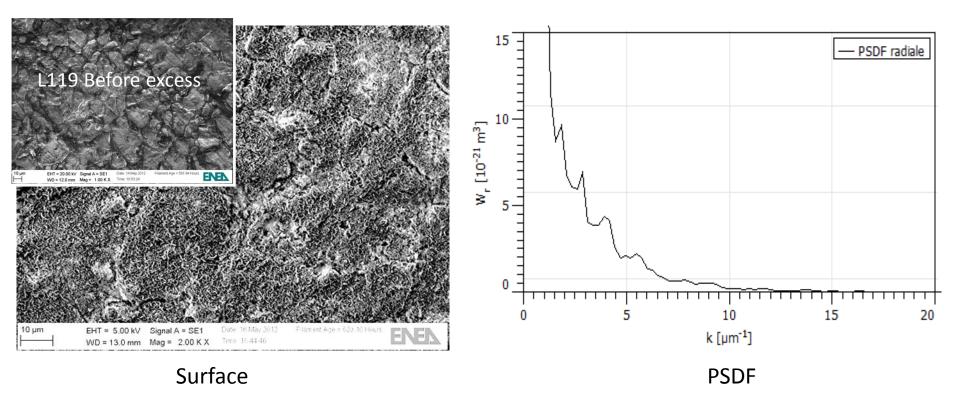


Loading is high and fast





L119 as was During the Excess



Cu, Fe,Si and Pt have been identified as contaminants on the electrode surface after the electrolysis.



Let see if we may extract any additional information from GEIS (Galvanostatic Electrochemical Impedence Spectroscopy) performed during the experiment.

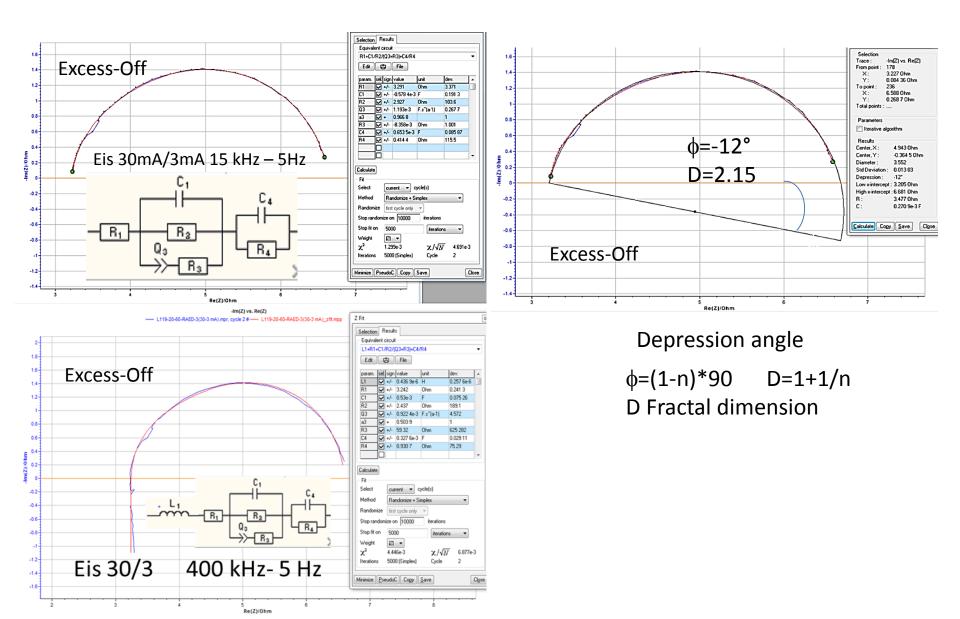
Typical GEIS Performed with Inactive Pd Foil

2.4-2.2-2. 1.8-1.6-1.4-30 mA + 3* sin(ωt) 1.2 -Im(Z)/0 hm 0.8 4 KHz 0.6 0.4 0.2-2Hz 100 mA + 10* sin(ωt) 0--0.2 -0.4 -0.6 5 7 8 3 6 9 Re(Z)/Ohm

GEIS at two DC current levels

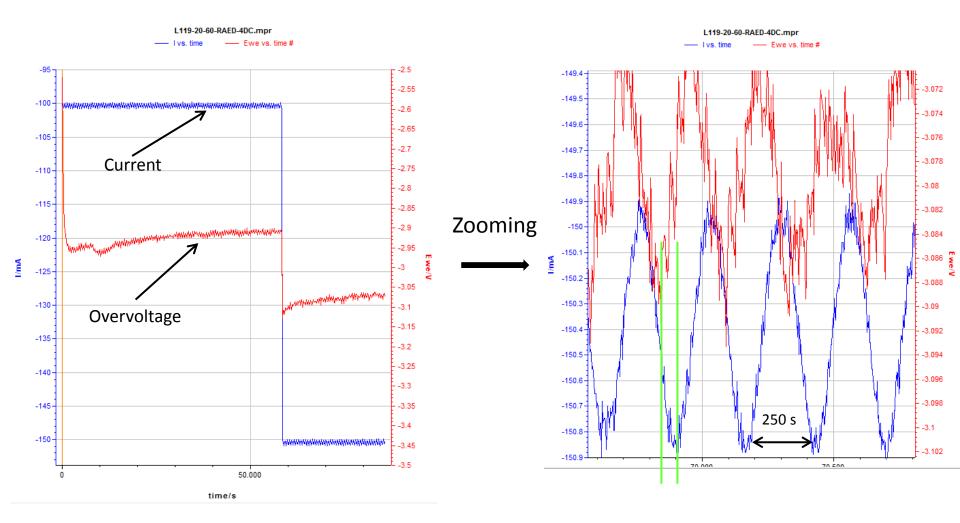


In Situ Electrochemical Impedence Spectroscopy on Sample L119(20-60) Excess-off





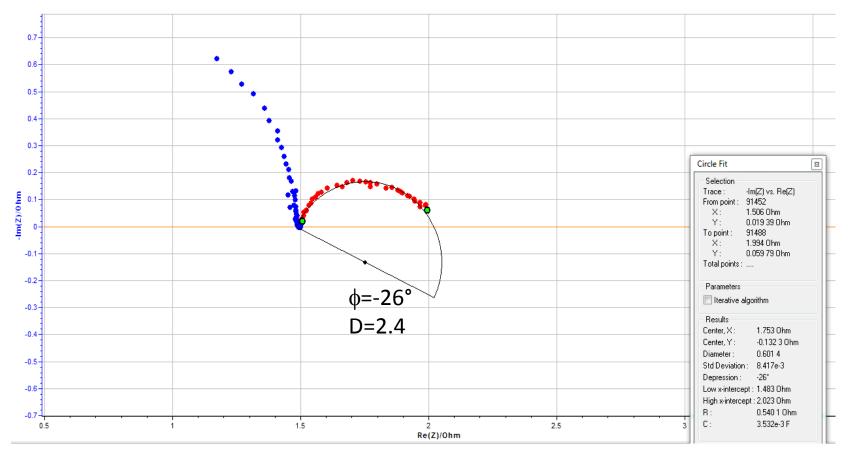
Current and overvoltage behavior during 40% excess



Note: Current ripple has been always observed in galvanostatic mode during significant excesses

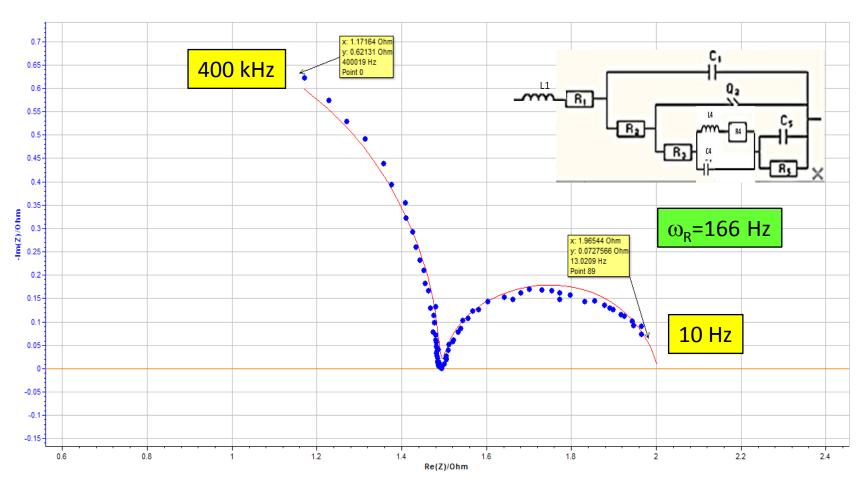


Something was changing at the interface during the excess !!





In Situ Electrochemical Impedence Spectroscopy on Sample L119(20-60) Excess-on



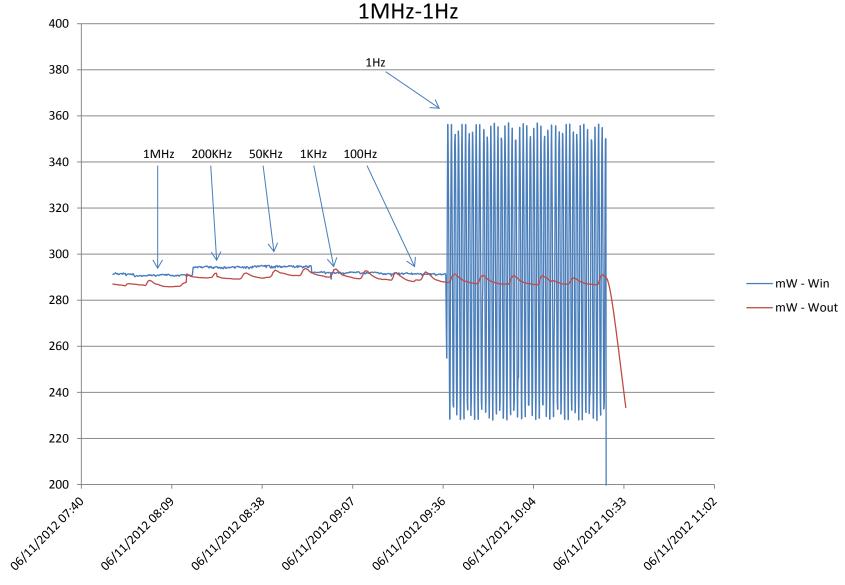
-Im(Z) vs. Re(Z)

L119-20-60-RAED-1(90-7 mA)_cycle11b.mpr # ____ L119-20-60-RAED-1(90-7 mA)_cycle11b_zfit.mpp

A wide range of resonating frequencies is possible



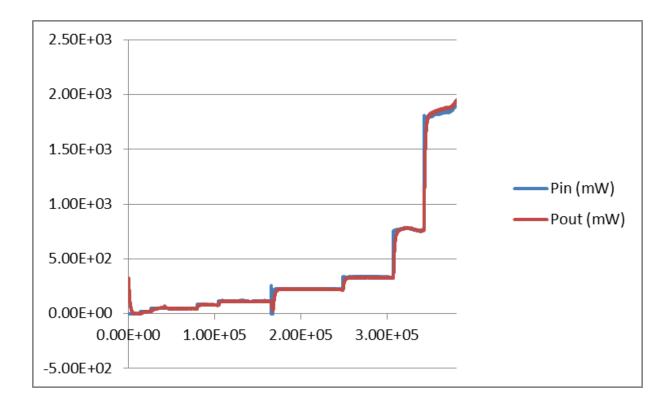
Calorimeter check: Pin-Pout by applying 100mA ± 20mA in the frequency range





Sample L119-140-180

Sample L119-140-180 was inactive, no evidence of specific contaminants on the surface



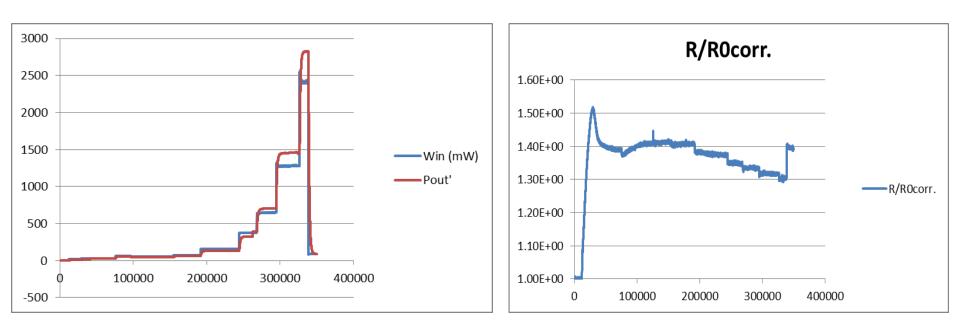
Pin-Pout Sample L119-140-180

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Again

L124(50-90) Excess



Pin - Pout L124(50-90)

Normalized resistance L124(50-90)

Loading is high and fast

Identified contaminants : same as L119(20-60)

This sample was the 'most close' to L119(20-60)



Conclusions

Material features , related with the occurrence of the effect, have been identified:
1) loading thereshold, 2) loading dynamics, 3)grain-grain boundary size,
4) surface morphology, 5) crystal orientation (Pd).

A specific role of some contaminants has been also identified.

In situ GEIS revealed a dramatic changing of the electric structure of the interface : resonating circuits components turn out during excess.

Material status is the key to observe the effect. Material science is the key to understand it, since some material characteristics support some processes rather than others.

By applying the scientific method future work should be oriented towards the definition of the effect rather than its demonstration.



Thank You

This work has been supported by National Instruments and a specific work is in progress to develop new instruments to improve the study.